

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination WEILLER ET AL.	
		Examiner Kaj K. Olsen	Art Unit 1753	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*	*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Reneker et al, Nanotechnology 7 (1996), pp. 216-223.
	V	
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